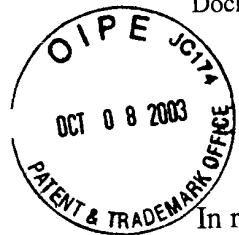


Docket No.: 87324.1800

PATENT/OFFICIAL



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Randall Malterer

Serial No. 10/626,713

Filed: July 25, 2003

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:  
: Group Art Unit: Unassigned  
:  
: Examiner: Unassigned

For: CHILL BLOCK AND METHODS FOR MANUFACTURING CHILL BLOCKS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

No further elaboration is believed necessary. Copies of the documents are submitted herewith in accordance with 37 C.F.R. §1.98(a).

AUTHORIZATION

This Information Disclosure Statement is being filed before receipt of the first Office Action. No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,

BAKER & HOSTETLER LLP

A handwritten signature in black ink, appearing to read 'Sunit Talapatra', with a long horizontal stroke extending to the right.

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# LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.  
87324.1800

SERIAL NO.  
10/626,713

APPLICANT  
Randall Malterer.

FILING DATE  
7/25/03

GROUP  
Unassigned

## U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		5,913,355	6/22/99	Muramatsu			
B		5,913,356	6/22/99	Muramatsu			
C							
D							
E							
F							
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## FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH	
II	
JJ	
KK	
LL	
MM	
NN	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.